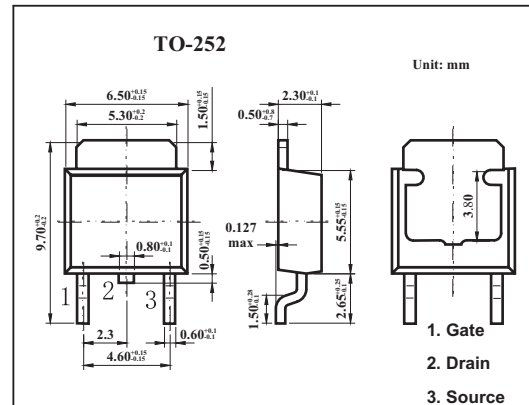
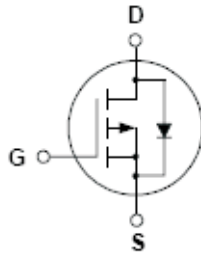


## 100V P-Channel MOSFET KQD5P10

### ■ Features

- -3.6A, -100V,  $R_{DS(on)} = 1.05 \Omega$  @  $V_{GS} = -10$  V
- Low gate charge ( typical 6.3 nC)
- Low  $C_{rss}$  ( typical 18 pF)
- Fast switching
- 100% avalanche tested
- Improved  $dv/dt$  capability



### ■ Absolute Maximum Ratings $T_a = 25^\circ\text{C}$

Parameter	Symbol	Rating	Unit
Drain to Source Voltage	$V_{DS}$	-100	V
Drain Current Continuous ( $T_c=25^\circ\text{C}$ )	$I_D$	-3.6	A
Drain Current Continuous ( $T_c=100^\circ\text{C}$ )		-2.28	A
Drain Current Pulsed *1	$I_{DM}$	-14.4	A
Gate-Source Voltage	$V_{GS}$	$\pm 30$	V
Single Pulsed Avalanche Energy*2	$E_{AS}$	55	mJ
Avalanche Current *1	$I_{AR}$	-3.6	A
Repetitive Avalanche Energy *1	$E_{AR}$	2.5	mJ
Peak Diode Recovery $dv/dt$ *3	$dv/dt$	-6	V/ns
Power dissipation @ $T_A=25^\circ\text{C}$	$P_D$	2.5	W
Power dissipation @ $T_c=25^\circ\text{C}$		25	W
Derate above $25^\circ\text{C}$		0.2	W/ $^\circ\text{C}$
Operating and Storage Temperature	$T_J, T_{STG}$	-55 to 150	$^\circ\text{C}$
Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds	$T_L$	300	$^\circ\text{C}$
Thermal Resistance Junction to Case	$R_{\theta JC}$	5	$^\circ\text{C}/\text{W}$
Thermal Resistance Junction to Ambient *4	$R_{\theta JA}$	50	$^\circ\text{C}/\text{W}$
Thermal Resistance Junction to Ambient	$R_{\theta JA}$	110	$^\circ\text{C}/\text{W}$

\*1 Repetitive Rating: Pulse width limited by maximum junction temperature

\*2  $I = 6.4$  mA,  $I_{AS} = -3.6$  A,  $V_{DD} = -25$  V,  $R_G = 25 \Omega$ , Startion  $T_J = 25^\circ\text{C}$

\*3  $I_{SD} \leq -4.5$  A,  $di/dt \leq 300$  A/ $\mu$ S,  $V_{DD} \leq B_{VDS}$ , Startiong  $T_J = 25^\circ\text{C}$

\*4 When mounted on the minimum pad size recommended (PCB Mount)

## KQD5P10

## ■ Electrical Characteristics Ta = 25°C

Parameter	Symbol	Testconditions	Min	Typ	Max	Unit
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	V <sub>GS</sub> = 0 V, I <sub>D</sub> = -250 μA	-100			V
Breakdown Voltage Temperature Coefficient	$\frac{\Delta BV_{DSS}}{\Delta T_J}$	I <sub>D</sub> = -250 μA, Referenced to 25°C		-0.1		mV/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = -100 V, V <sub>GS</sub> = 0 V			-1	μA
		V <sub>DS</sub> = -80 V, T <sub>C</sub> = 125°C			-10	μA
Gate-Body Leakage Current, Forward	I <sub>GSSF</sub>	V <sub>GS</sub> = -30 V, V <sub>DS</sub> = 0 V			-100	nA
Gate-Body Leakage Current, Reverse	I <sub>GSSR</sub>	V <sub>GS</sub> = 30 V, V <sub>DS</sub> = 0 V			100	nA
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = -250 μA	-2.0		-4.0	V
Static Drain-Source On-Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = -10 V, I <sub>D</sub> = -1.8A		0.82	1.05	Ω
Forward Transconductance	g <sub>FS</sub>	V <sub>DS</sub> = -40 V, I <sub>D</sub> = -1.8A *		2.3		S
Input Capacitance	C <sub>iss</sub>	V <sub>DS</sub> = -25 V, V <sub>GS</sub> = 0 V, f = 1.0 MHz		190	250	pF
Output Capacitance	C <sub>oss</sub>			70	90	pF
Reverse Transfer Capacitance	C <sub>rss</sub>			18	25	pF
Turn-On Delay Time	t <sub>d(on)</sub>	V <sub>DD</sub> = -50 V, I <sub>D</sub> = -4.5A, R <sub>G</sub> = 25 Ω *		9	30	ns
Turn-On Rise Time	t <sub>r</sub>			70	150	ns
Turn-Off Delay Time	t <sub>d(off)</sub>			12	35	ns
Turn-Off Fall Time	t <sub>f</sub>			30	70	ns
Total Gate Charge	Q <sub>g</sub>	V <sub>DS</sub> = -80V, I <sub>D</sub> = -4.5A, V <sub>GS</sub> = -10 V *		6.3	8.2	nC
Gate-Source Charge	Q <sub>gs</sub>			1.7		nC
Gate-Drain Charge	Q <sub>gd</sub>			3.0		nC
Maximum Continuous Drain-Source Diode Forward Current	I <sub>S</sub>				-3.6	A
Maximum Pulsed Drain-Source Diode Forward Current	I <sub>SM</sub>				-14.4	A
Drain-Source Diode Forward Voltage	V <sub>SD</sub>	V <sub>GS</sub> = 0 V, I <sub>S</sub> = -3.6 A			-4.0	V
Diode Reverse Recovery Time	t <sub>rr</sub>	V <sub>GS</sub> = 0 V, dI <sub>F</sub> /dt = 100 A/μs, I <sub>S</sub> = -4.5A *		85		ns
Diode Reverse Recovery Current	Q <sub>rr</sub>			0.27		μC

\* Pulse Test: Pulse Width ≤ 300 μs, Duty Cycle ≤ 2.0%